

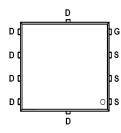
# SSF3115J7

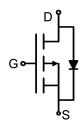
## Main Product Characteristics:

V <sub>DSS</sub>	-30V		
R <sub>DS</sub> (on)	10 mΩ (typ.)		
ID	-26A		



PDFN 5\*6-8L





**Pin Assignments** 

Schematic Diagram

#### Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



### **Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

### Absolute max Rating:

Symbol	Symbol Parameter			
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, ①	-26	Δ	
I <sub>DM</sub>	Pulsed Drain Current ②	-130	A	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation ③	69	W	
V <sub>DS</sub>	Drain-Source Voltage	-30	V	
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V	
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C	



## **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
Rejc	Junction-to-Case (t $\leq 10$ s) $\textcircled{4}$	_	1.8	°C <b>/W</b>

#### Electrical Characterizes @TA=25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	-30	_		V	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250µA	
Р	Static Drain-to-Source on-resistance	_	10	14	mΩ	V <sub>GS</sub> =-10V,I <sub>D</sub> = -8A	
$R_{DS(on)}$		_	15	19	mΩ	V <sub>GS</sub> =-4.5V,I <sub>D</sub> =-4A	
$V_{\text{GS(th)}}$	Gate threshold voltage	-1	_	-3	V	$V_{DS} = V_{GS}, I_D = -250 \mu A$	
I <sub>DSS</sub>	Drain-to-Source leakage current	_	_	-1	uA	$V_{DS} = -30V, V_{GS} = 0V$	
	Coto to Source ferruard looke re	_	_	100		V <sub>GS</sub> = 20V	
I <sub>GSS</sub>	Gate-to-Source forward leakage	_	_	-100	nA	V <sub>GS</sub> = -20V	
Qg	Total gate charge	_	50			I <sub>D</sub> = -20A,	
Q <sub>gs</sub>	Gate-to-Source charge		7		nC	V <sub>DS</sub> =-15V,	
Q <sub>gd</sub>	Gate-to-Drain("Miller") charge	_	10	_		V <sub>GS</sub> = -10V	
t <sub>d(on)</sub>	Turn-on delay time	_	17.6	_			
tr	Rise time	_	34.1	_	]	$V_{GS}$ =-10V, $V_{DS}$ =-10V,	
t <sub>d(off)</sub>	Turn-Off delay time	_	24.9	_	ns	R <sub>GEN</sub> =3Ω,I <sub>D</sub> =-20A	
t <sub>f</sub>	Fall time	_	19.8				
Ciss	Input capacitance	_	2020	_		V <sub>GS</sub> = 0V	
Coss	Output capacitance	_	242	_	pF	V <sub>DS</sub> = -20V	
C <sub>rss</sub>	Reverse transfer capacitance	_	229	_	1	f = 1MHz	

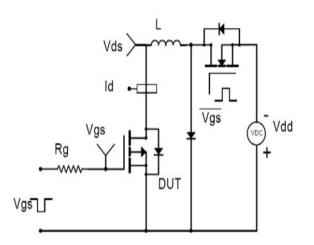
# Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			-26 A	^	MOSFET symbol □ ঢ
Is	(Body Diode)				A	showing the
ISP	Pulsed Source Current	_	_	-130	А	integral reverse G⊶ → ♥
	(Body Diode)					p-n junction diode. $r_{s}$
V <sub>SD</sub>	Diode Forward Voltage	—		-1.2	V	I <sub>S</sub> =-20A, V <sub>GS</sub> =0V

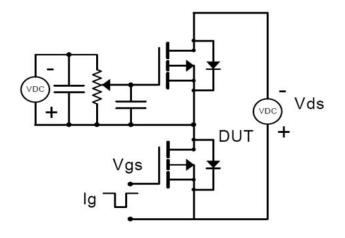


## **Test Circuits and Waveforms**

EAS Test Circuit:

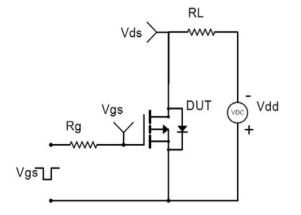


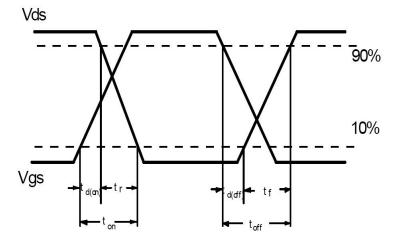
Gate Charge Test Circuit:



Switching Time Test Circuit:

Switching Waveforms:





### Notes:

- $(\ensuremath{\texttt{ICalculated}}\xspace$  continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- (4) The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^{\circ}C$



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## **Typical Electrical and Thermal Characteristics**

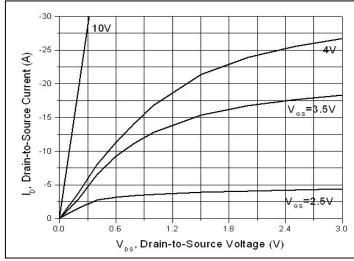


Figure 1. Typical Output Characteristics

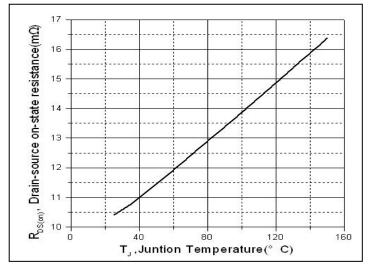


Figure 3. Normalized On-Resistance vs. Junction Temperature

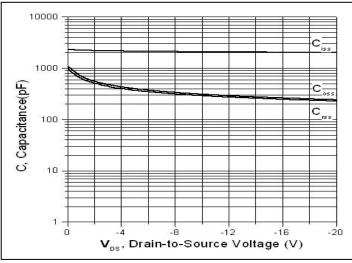
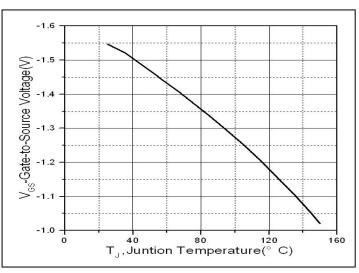
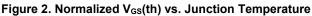


Figure 5. Capacitance Characteristics





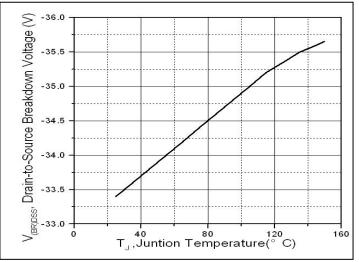
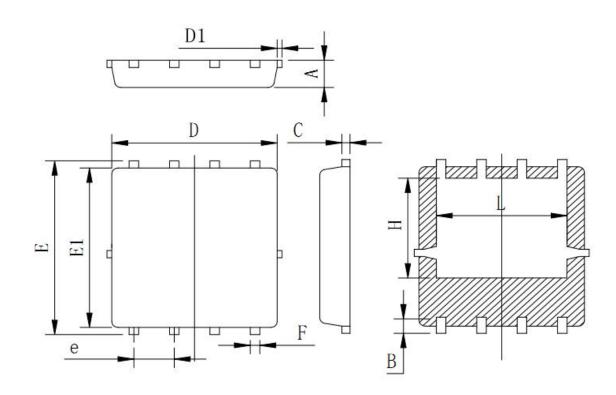


Figure 4. Drain-to-Source Breakdown Voltage vs. Junction Temperature



## Mechanical Data:

PDFN 5\*6 Package Outline (Unit: mm)



Symbol	Min	Тур	Max
Α	0.90	0.95	1.00
В	0.48	0.58	0.68
С	0.20	0.254	0.30
D	5.00	5.20	5.40
Dl			0.15
E	5.90	6.05	6.20
El	5.40	5.55	5.70
e	1.22	1.27	1.32
F	0.25	0.30	0.35
Н	3.27	3.47	3.67
L	3.80	4.00	4.20



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